

<b>Notice of References Cited</b>	Application/Control No. 10/565,719	Applicant(s)/Patent Under Reexamination ADUR, ASHOK M.	
	Examiner Jeffrey Lenihan	Art Unit 1796	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	K	US-			
	L	US-			
	M	US-			

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